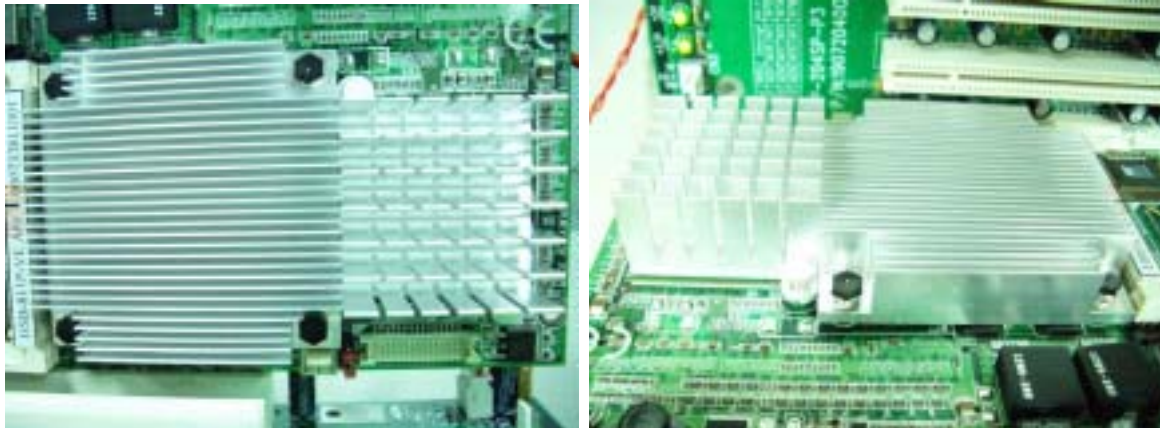


1. <i>Test item list</i> -----	2
2. <i>Temperature cycle operation test</i> -----	3
3. <i>High temperature storage test</i> -----	7
4. <i>Low temperature storage test</i> -----	9
5. <i>Humidity test</i> -----	10
6. <i>Cold start test</i> -----	11

Test Configuration:

Num	Item	Spec
1.	Control Box:	AMC- 250 / 5 Slot Wall Mounting Chassis
	1. Backplanes	BP-205SP-P4 Rev A1.1
	2. Main Board	AAEON HSB-811P A0.1 (BIOS: 1.0)
	3. CPU	Intel Celeron (R) 600MHz (100x6.0)
	4. Memory	256MB Hynix HY5DU56822BT-043 (DDR 400)
	5. Power Supply	Enhance ENP-1815 / 150W (ATX)
	6. HDD	Seagate ST340014A 40GB
	7. FDD + Card Reader	TEAC FD-CR7

CPU and North Bridge Heat Sink



Test Date: 05-09~12-2005

Test Product: AMC-250 (HSB-811P A0.1).

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

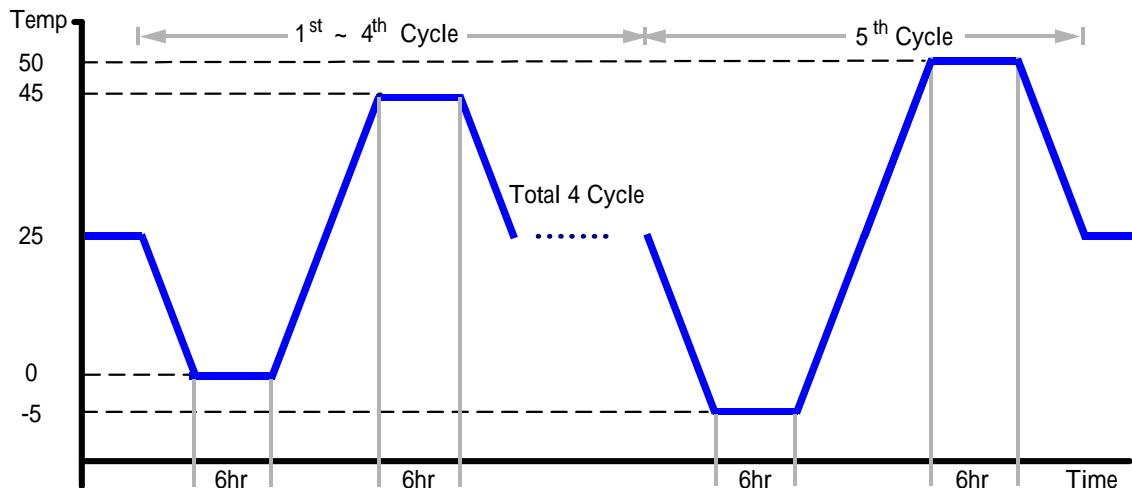
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/24/04
Serial Number: 1241

Temperature Measurement:

20 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/25/04
Serial Number: 12A323190

Test Condition:

- Test Low Temperature: 0 (1~4 cycle)
-5 (5th cycle)
- Test High Temperature: 45 (1~4 cycle)
50 (5th cycle)
- Test dwell time: 6Hrs
- Temperature slope: 1 /min
- Test cycle: 5 cycle
- Test Environment Curve:



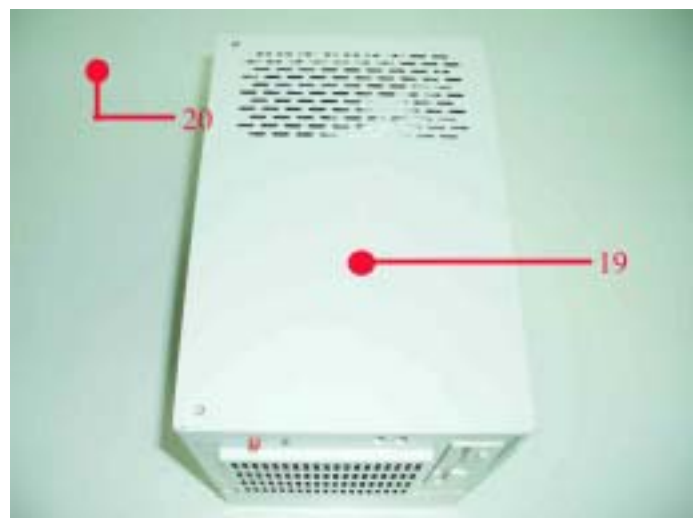
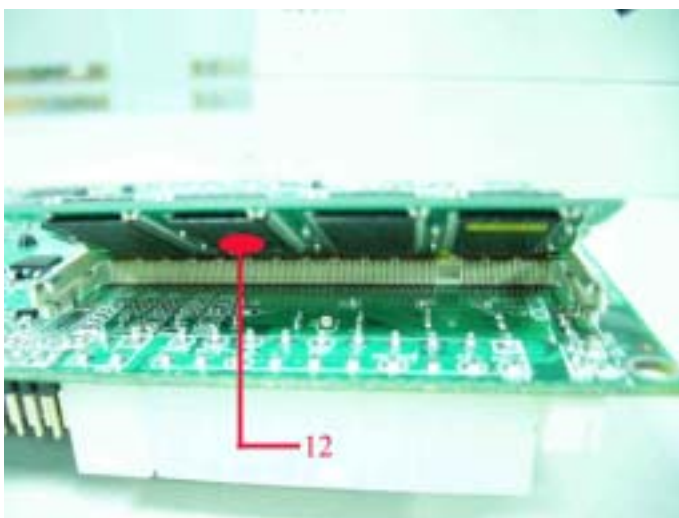
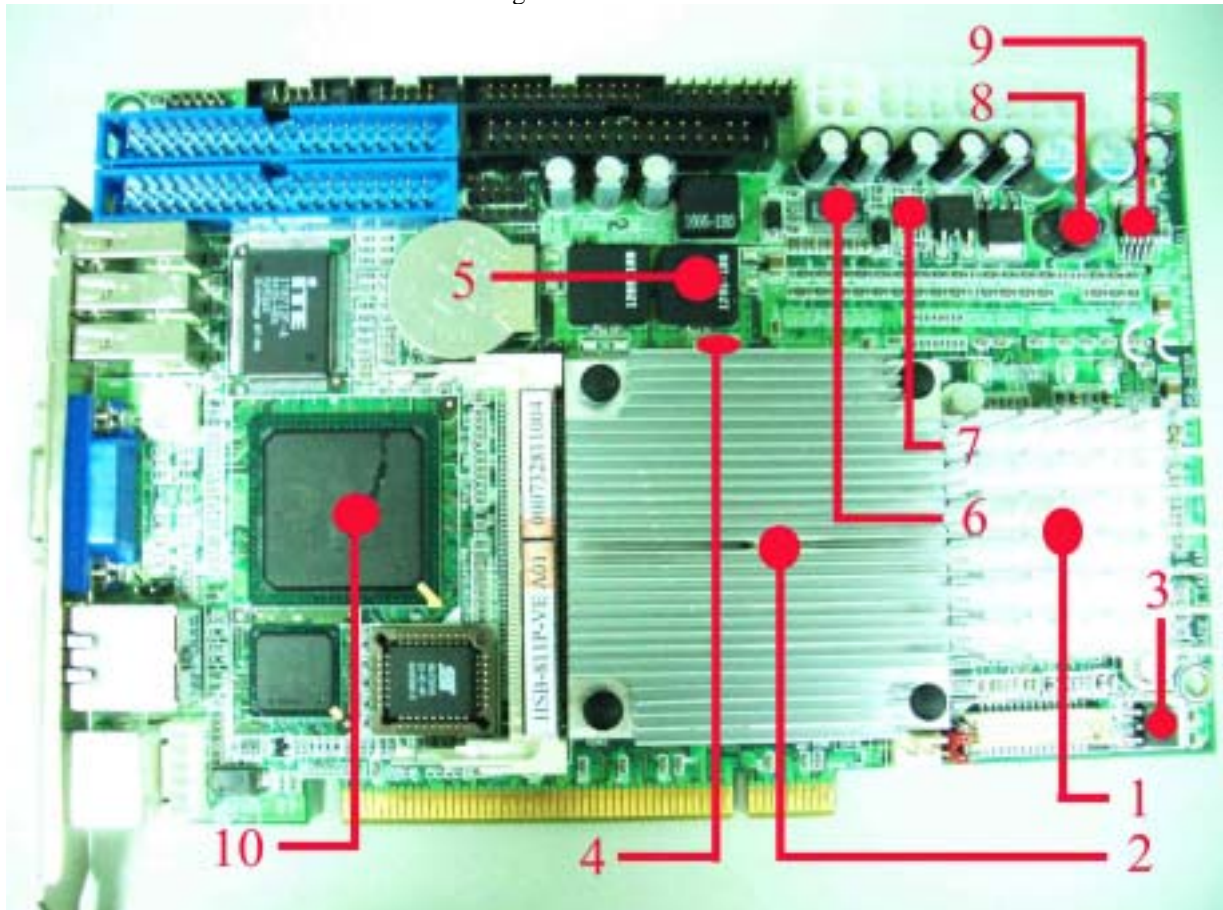
Test O.S. / Software:

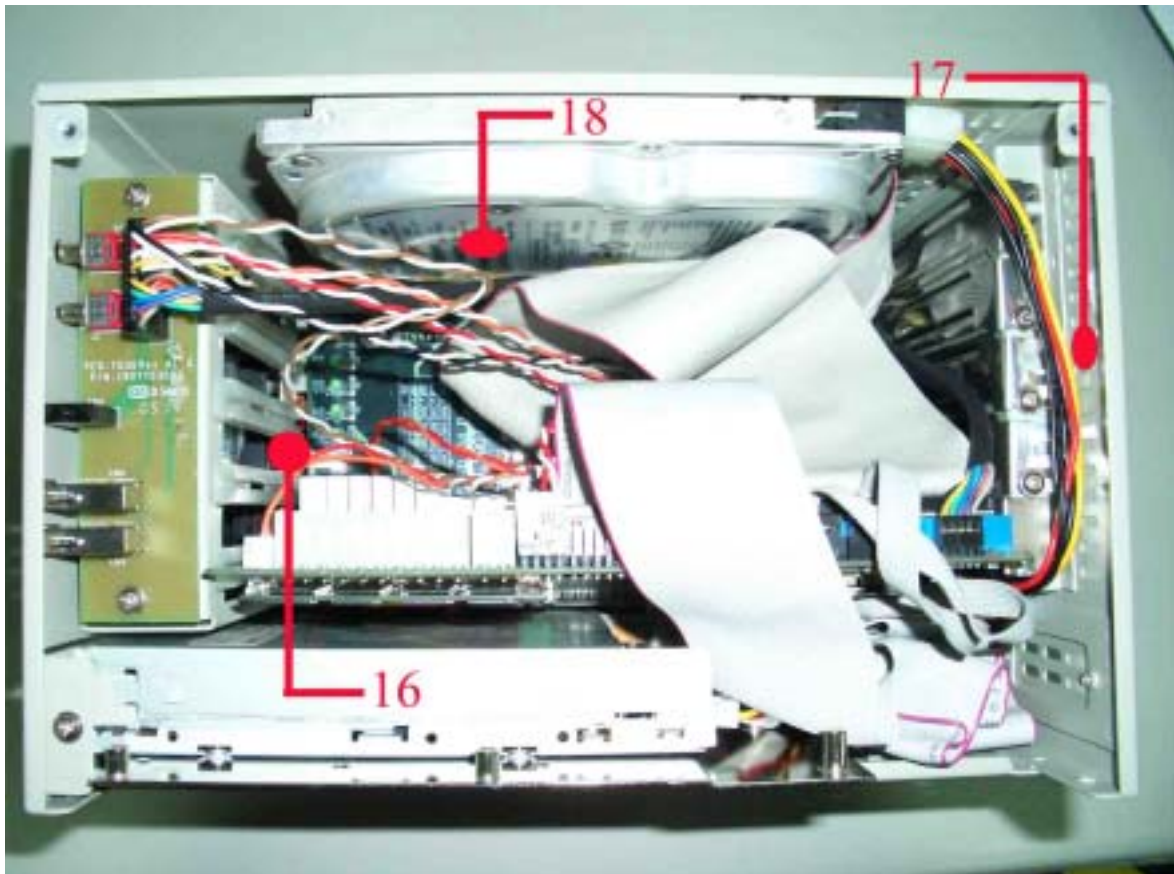
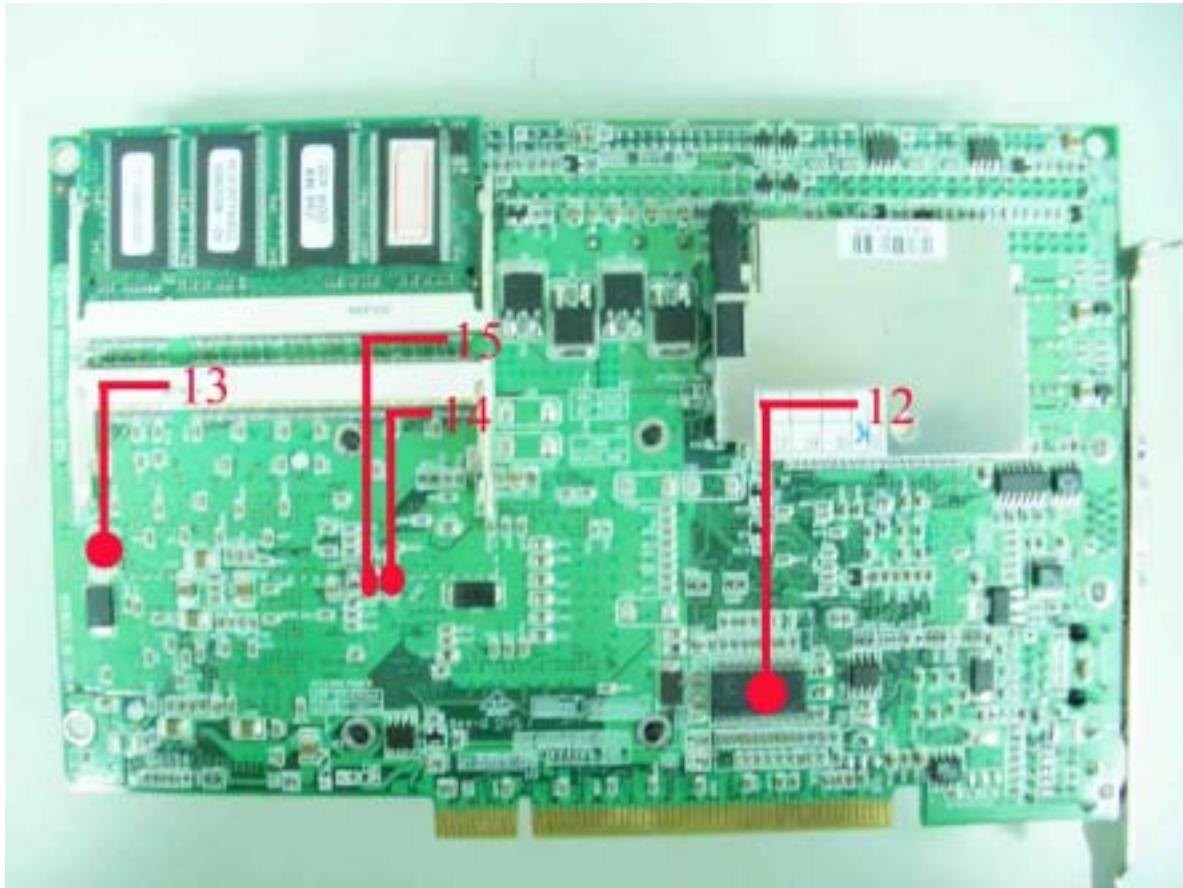
Windows 2000 / Run HCT 9.5

Sample Configuration & Quantity Under Test:

Using one AMC-250 (HSB-811P A0.1) Wall-Mount IPC System Recorder:

Measuring Accelerometer Position:





Thermal profile data:

AMC-250 (HSB-811P A0.1)

Point	Temp. Stage	55	50	25	0	-5	Tc
1. U8 - Chipset.NB82852GM.Intel.RG82852GM-SL6ZK		67.7	62.5	37.6	11.9	7.0	110
2. CPU1 - INTEL CPU.Celeron-M.ULV 600MHz		74.3	68.8	42.0	15.4	10.6	0~100
3. Q3 - REG.SMD.TO-252 5A LinearRegulator.ATC.AP1084D-ADJ		69.3	63.8	38.8	12.6	8.0	30~120
4. C110 - Panasonic EEFSX0D221YR/SP CAP.220uF.2V.-35~+10%.		71.4	65.7	39.6	13.5	8.4	-40~105
5. L10 - COIL.1.0uH.SMD.DCR=3mohm Idc=25Amp.ESPI-1206-1R0M		68.8	63.5	37.6	12.4	7.2	-25~100
6. U1 - SEMTECH/SC1476ITSTR/IC.SMD TSSOP-38 IMVP4.Dual Phase PWMControlle		69.6	63.8	39.1	13.5	8.8	0~125
7. U34 - IC.SMD SOP.8Pin Switching PWMController.IR.IRU3037CS		73.5	67.6	43.4	17.8	13.1	74
8. L5 - COIL.3.3uH 6.4A.20%.SMD.YC0804-3R3;EE-A041504		66.4	60.3	36.2	10.8	6.0	-25~85
9. Q1 - REG.SMD TO-252-5.2A Bus TerminationRegulator.RichTek.RT9173BCL5		64.9	58.9	34.4	9.5	4.3	-10~95
10. U5 - INTEL/FW82801DB SL6DM/IC.SMD.Chipset ICH4.INTEL.FW82801DBSL6DM		68.7	63.4	38.8	13.8	8.5	-0~110
11. Memory		73.6	65.5	43.8	18.5	14.5	-
12. U30 - IC.SMD.SSOP 48Pin ClockGenerator.ICS.ICS952607		83.8	78.0	54.2	29.6	24.6	-25~115
13. U33 - PWR.SMD SO-8.DUAL N-Channel 30(D-S)MOSFET.VISHAY.SI4920DY		93.3	86.9	62.7	37.7	31.9	-25~100
14. U27 - PWR.SMD SO-8.DUAL N-Channel 30(D-S)MOSFET.VISHAY.SI4920DY		77.3	70.5	46.0	20.1	15.4	-25~100
15. U28 - IC.SMD MSOP-10.Dual Linear FETController.SEMTECH.SC3381MSTR		71.9	65.8	40.6	14.6	9.9	-40~120
16. Inside Air Temperature - 1		58.9	53.8	29.2	4.0	-1.0	-
17. Inside Air Temperature - 2		59.1	53.9	29.3	4.0	-1.1	-
18. HDD		59.1	53.7	29.5	4.1	-0.7	0~60
19. Control Box. External Surface		57.1	52.0	27.4	2.4	-2.6	-
20. Chamber Air Temperature		55.5	50.4	25.5	0.6	-4.6	-

Note: The description in red states which temperature is over the specification of the device.

Sample Configuration & Quantity Under Test:

Quantity: 1 (AMC-250)

Test Result:

The system structure doesn't deformation; Function is passed during system test.

Test Date: 05-05~08-2005

Test Product: AMC-250 (HSB-811P A0.1).

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 10/01/04

Serial Number: 2582

Testing Item:

1. Test Temperature: 60
2. Test Times: 48Hrs
3. Test Software: Windows media Player (Video test soft-MPEG from HDD)
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AMC-250)

Test Result:

The system structure doesn't have any deformation; All functions are passed after low temperature storage test.

Test Date: 05-14~16-2004

Test Product: AMC-250 / 5 Slot Wall Mounting Chassis

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

- 5. Test Temperature: 80
- 6. Test Times: 48Hrs
- 7. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AMC-250 / 5 Slot Wall Mounting Chassis)

Test Result:

After high temperature storage test, the structure of chassis never change shape and surface paint doesn't flake off.

Test Date: 05-02~05-2005

Test Product: AMC-250 (HSB-811P A0.1).

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: TS-F3L+-100
Date of Calibration: 04/01/04
Serial Number: 1467

Testing Item:

1. Test Temperature: -20
2. Test Times: 48Hrs
3. Test Software: Windows media Player (Video test soft-MPEG from HDD)
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AMC-250)

Test Result:

The system structure doesn't have any deformation; All functions are passed after low temperature storage test.

Test Date: 04-29~05-01-2005

Test Product: AMC-250 (HSB-811P A0.1).

Test Site: AAEON QA Internal Lab.

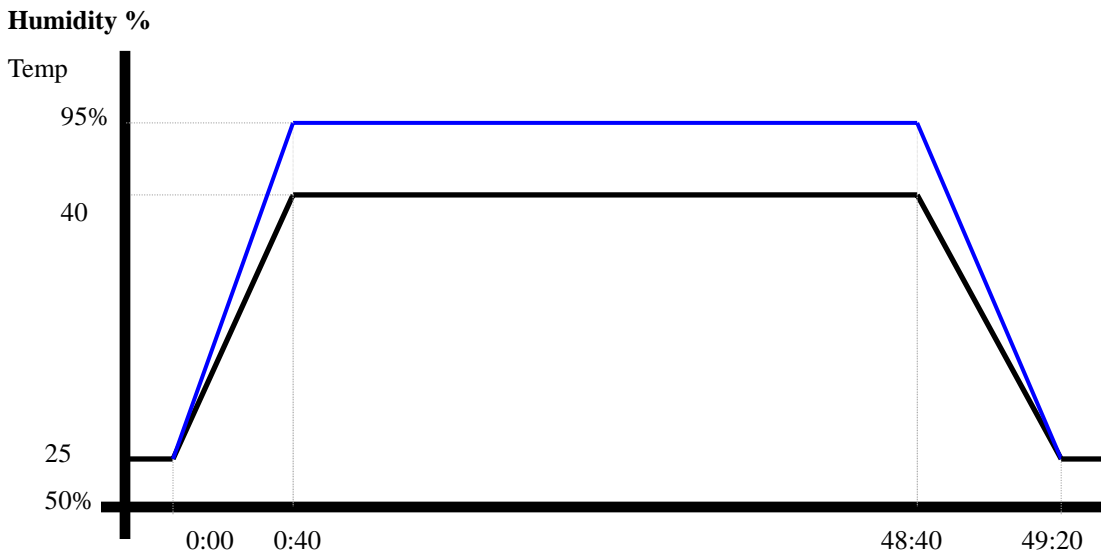
Performed By: Rex Chang

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/01/04
Serial Number: 2582

Testing Item:

1. Test Temperature: 40
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows media Player (Video test soft-MPEG from HDD)
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AMC-250)

Test Result:

The system structure doesn't have any deformation; All functions are passed after humidity test.

Test Date: 05-02-2005

Test Product: AMC-250 (HSB-811P A0.1).

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

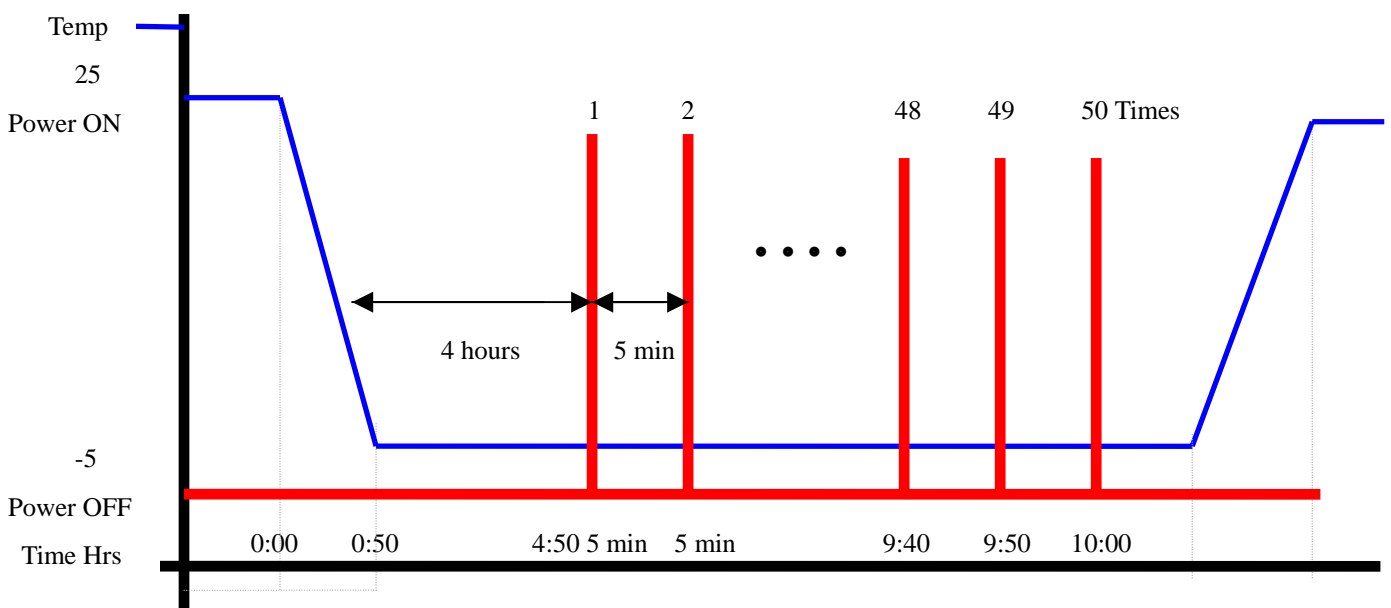
Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/01/04
Serial Number: 2582

Test Condition:

1. Test Temperature: -5
2. Test Times: 5 Hours or 50 times of ON/OFF
 - (1) Power off for 4 hours before 1'st power on. Then once complete boot, power off immediately.
 - (2) After 5 min later power on again and wait until booting is completed.
 - (3) Repeat (2) for around 4:50
 - (4) Power off then wait for 5 min before final power on operation.
3. Number of test: 50 times
4. Test Software: Windows 2000
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AMC-250)

Test Result:

Passed.